

Application/Control No.	Applicant(s)/Patent und Reexamination	ier
09/666,485	TEZUKA ET AL.	
Examiner	Art Unit	
Oanh Duong	2155	

	SEARCHED			
Class	Subclass	√Date	Examiner	
709	202, 223- 224, 246, 249-250	9/4/2005	o.d	
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
709	224, 246	9/4/2005	O.D		
709	249	9/4/2005	o.d		
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
EAST text search of USPAT, JPO, EPO, DERWENT, IBM-tdb, US- PGPUB	9/4/2005	O.D
RFC index search engine	9/5/2005	O.D